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06-17-03
PATENTS I

Docket No. 12219/7

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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MAY 14 2003
TECHNOLOGY CENTER 2800

APPLICANTS: Yuji MIYAUCHI et al.
SERIAL NO. : 10/050,881 *2612*
FILED : 18 January 2002
FOR : IMAGE PICKUP SYSTEM

COMMISSIONER FOR PATENTS
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98**

S I R:

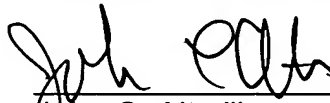
In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(3), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

In accordance with the requirements of 37 C.F.R. § 1.98, copies of the references are submitted herewith.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

Dated: 13 May 2003



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FORM PTO-1449
INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)

Atty Docket No. : 12219/7
 Serial No. : 10/050,881
 Inventors : Yuji MIYAUCHI et al.
 Filed : 18 January 2002
 Group Art Unit : 2612
 Examiner :



U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/ Subclass</u>	<u>Filing Date</u>
	6,308,011	10/23/01	WACHI et al.	396/72	
	6,185,048	02/06/01	ISHII	359/687	
	6,331,917	12/18/01	ISHII et al.	359/687	
	2002/0057502	05/16/02	ISHII et al.	359/687	
	6,124,984	09/26/00	SHIBAYAMA et al.	359/687	

FOREIGN PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/ Subclass</u>	<u>Translation Yes No</u>
	2000-275520	10/06/00	Japan		X
	2000-267009	09/29/00	Japan		ABS.
	1 093 000	04/18/01	EPO		N/A

OTHER DOCUMENTS

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner
Initial

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.